# PER-C37L Environment Test Report

Report NO: 13I020028

	<b>▽</b> Pass
	□ Fail
Summary	Note: There is/are defect(s) not list in the report, please check it in the DTS Website.
	☐ Pass with Deviation
	Comment:

<b>Issue date</b>	Approval	<b>Issued by</b>
2013-10-23	Tom Lin	Juno Cheng

## **Test item list**

<i>1</i> .	Test item list	2
<i>2</i> .	Configuration of EUT	3
<i>3</i> .	Temperature rise test	5
<i>4</i> .	Temperature cycle operation test	9
<i>5</i> .	High temperature storage test	<i>10</i>
<i>6</i> .	Low temperature storage test	<i>11</i>
<i>7</i> .	Humidity test	<i>12</i>
	Cold start and hot start test	<i>13</i>

## **Testing Result**

Num	Test item list	Result	Remark
1	Temperature rise test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

# **Configuration of EUT**

Num	Item	Spec
1.	PCI-Express 1G Ethernet Module	PER-C371L
2.	Host System:	FWS-7810
	1. Main board	FWB-7810 A1.0
	2. BIOS	FWS-7810 R0.B (FW78ATOB) (08/03/2013)
	3. CPU Type	Intel Xeon CPU E3-1275 V3
	4. Memory	DSL DDR3 1333 4GB CL9*4
	5. 3.5" SATA HDD	Western Digital WD3200AAKX 3.5" 320GB
	7. Test Software	Windows 7 / Run BurnIn test 7.0 Pro
3.	Power Supply	FSP250-50LC

## **CPU** Cooler





## **Temperature rise test**

**Test Date:** 10-21~22-2013

**Test Product: PER-C37L** 

Test Site: AAEON QE Dept.

**Test Standard:** Refer to EN 61131-2(94), UL508 (94)

**Temperature Measurement:** 

40 Channel Thermal Recorder: (YOKOGAWA Inc,)

Model: DA100-13-1D

Date of Calibration: 10/01/13 Serial Number: 12A323190

**Test Condition:** 

Ambient temperature: 40°C

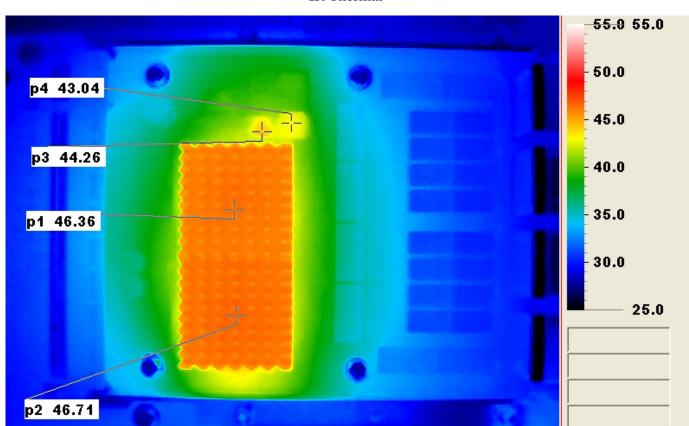
Continuous running till thermal stability (within less than 1°C)

**Test Software:** 

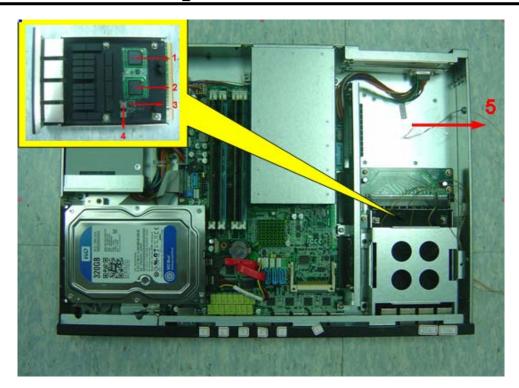
Windows 7 / Run PassMark Burn In Test 7.0 Pro

#### **Terminal Recorder:**

#### IR Thermal



## **Temperature rise test**





## **Temperature rise test**

#### Thermal profile data:

#### PER-C37L

Point Temp. Stage(°C)	Spec	40°C	25°℃	Note
01. U11–(TF) PCI-E.GbE Controller.Qual Port.Intel.I350-AM4	85	53.9	38.9	
02. U12 – (TF) PCI-E.GbE Controller.Qual Port.Intel.I350-AM4	85	53.0	38.0	
03. Q22 - (TF)PWR. N-Ch Enhancement Mode. MOSFET.Sinopower.APM7334KC-TRG	150	51.9	36.9	
04. L34 (TF)COIL.3.3uH GOTREND.GSTC063P-3R3MN		50.7	35.7	
05. System inside air temperature		41.2	26.2	
06. Chamber Air Temperature	N/A	40.0	25.0	

#### **Note(\*):**

- 1. "Tc" indicates the component's case maximum temperature value specified in its datasheet.
- 2. "Tm" indicates the measured Tc value under working environmental temperature within product specification.
- 3. Judgment Criteria:
  - Fail : Tm > Tc; The measured value is over specification.
  - Margin Pass:  $Tc > Tm > Tc-5^{\circ}C$ ; The measured value is within specification with margin.

It is strongly recommended to add thermal dissipation design for better reliability.

- **Pass** :  $Tm < Tc-5^{\circ}C$ ; The measured value is with safety margin.

#### **Sample Configuration & Quantity Under Test:**

Quantity: 1 (PER-C37L)

#### **Test Result:**

No issues were found during the temperature rise operation test.

## Temperature cycle test

**Test Date :** 10-21 ~ 19-2013

**Test Product:** PER-C37L

Test Site: AAEON QE Dept.

**Test Standard:** Refer to IEC68-2-14 Testing procedures

Test N: Change of temperature Test

**Test Equipment:** 

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)

Model: THS-D7S-100+1 N2 Date of Calibration: 09/16/'13

Serial Number: 3898

**Test Condition:** 

1. Test Low Temperature:  $0^{\circ}$ C (1~3 cycles)

 $-5^{\circ}$ C (4<sup>th</sup> cycle)

2. Test High Temperature: 40°C (1~3 cycles)

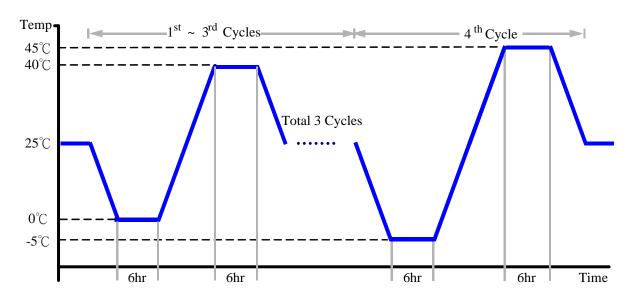
45°C (4<sup>th</sup> cycle)

3. Test dwell time: 6Hrs

4. Temperature slope: 2°C/min

5. Test cycle: 4 cycles

6. Test Environment Curve:



#### **Sample Configuration & Quantity Under Test:**

Quantity: 1 (PER-C37L)

**Test Result:** 

No issues were found during the temperature operation cycle test.

### **High temperature storage test**

**Test Date:** 10-19 ~ 17-2013

**Test Product: PER-C37L** 

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-2 Testing procedures

Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:** 

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)

Model: THS-D7S-100+1 N2 Date of Calibration: 09/16/'13

Serial Number: 3898

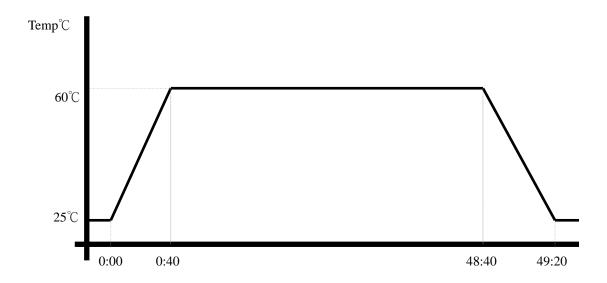
**Testing Item:** 

1. Test Temperature: 60°C

2. Test Times: 48Hrs

3. Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro

4. Test Environment Curve:



#### Sample Configuration & Quantity Under Test:

Quantity: 1 (PER-C37L)

#### **Test Result:**

No issues were found after the high temperature storage test.

## Low temperature storage test

**Test Date:** 10-17 ~ 16-2013

**Test Product:** FWS-7810

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-1 Testing procedures

Test Ab: Cold Test (Non-operation)

**Test Equipment:** 

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)

Model: THS-D7S-100+1 N2 Date of Calibration: 09/16/'13

Serial Number: 3898

**Testing Item:** 

1. Test Temperature: -20°C

2. Test Times: 48Hrs

3. Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro

4. Test Environment Curve:



#### Sample Configuration & Quantity Under Test:

Quantity: 1 (PER-C37L)

#### **Test Result:**

No issues were found after the low temperature storage test.

## **Humidity test**

**Test Date: 10-16 ~ 14-2013** 

**Test Product: PER-C37L** 

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-3 Testing procedures

Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:** 

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)

Model: THS-D7S-100+1 N2 Date of Calibration: 09/16/'13

Serial Number: 3898

**Testing Item:** 

1. Test Temperature: 40°C

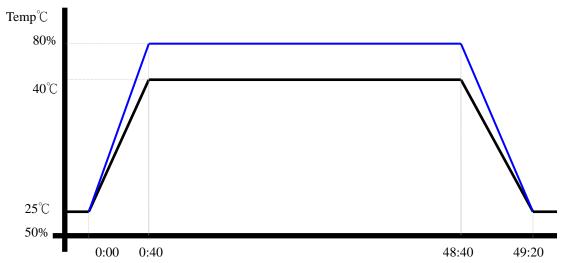
2. Test Humidity: 80%RH

3. Test Times: 48Hrs

4. Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro

5. Test Environment Curve:

#### **Humidity %**



#### **Sample Configuration & Quantity Under Test:**

Quantity: 1 (PER-C37L)

#### **Test Result:**

No issues were found after the humidity storage test.

## Cold start and hot start test

**Test Date: 1**0-14~ 12-2013

**Test Product: PER-C37L** 

Test Site: AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-14 Testing procedures

Test N: Change of temperature Test

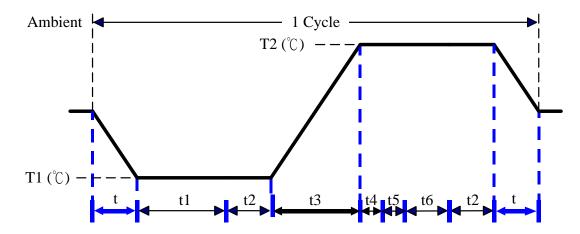
**Test Equipment:** 

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP)

Model: THS-D7S-100+1 N2 Date of Calibration: 09/16/'13

Serial Number: 3898

#### **Test Condition:**



Parameters	Description
T1	-5°C
T2	45°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

 $t = temprature \ slope$ 

t, t1, t6: Power Off

t2: Power on/off test 10 times (on 2 min / off 5min)

t3, t4: Run burn in test 7.0

t5: Win 7 Software restart test 3 times

Test Software: Windows 7

#### **Test Result:**

a. No issues were found during the cold start test.

b. No issues were found during the hot start test.